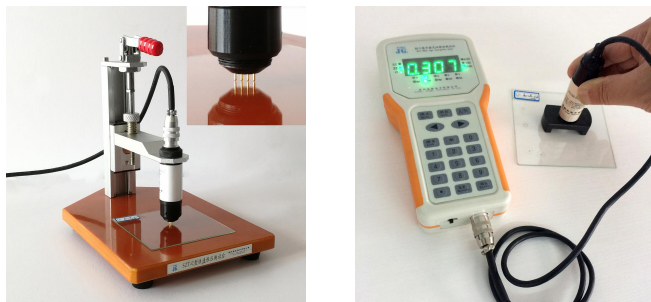


1. Overview of functions and structural features



ST2258B-F01 thin film square resistance linear four-probe test probe

Basic function: ST2258B-F01 thin-film square resistance linear four-probe probe, linear 2+2+2 mm needle pitch, spherical tip gold-plated phosphor copper alloy probe, equipped with four-probe instrument and test bench for testing flexibility Material Conductive film, metal coating or film, conductive film (ITO film) on the substrate such as ceramic or glass, or nano-coating resistivity/square resistance of semiconductor materials.

Basic composition: The complete set of probes consists of detachable probes, probe holders, hand-held jackets, test bench connection units, instrument connection cables and other components.

Matching and Compatibility: This probe is compatible with all four-probe instruments and four-probe test benches of our company. The main models in the table below are compatible with most of the four-probe instruments of other manufacturers.

2. Main technical parameters and description

1 Measurable pieces or bars can be measured. The minimum sample size is $3\text{mm} \times 10\text{mm}$, and the maximum plane size and thickness are determined by the equipped test bench. There is no limit to the way of holding the probe.

2.1 Probe pitch: straight line 2+2+2 mm pitch.

2.2 Probe mechanical movement rate: $\pm 0.5\%$.

2.3 Probe: gold-plated phosphor copper alloy, $\Phi 0.75\text{mm}$.

2.4 Pressure: 0~500g adjustable, rated pressure is about 400g.

3 The probe is a quick-release type, which is convenient for the frequent use of the production line.